



Joint Institute for Nuclear Research
Frank Laboratory of Neutron Physics

JINR Summer student practice

ION BEAM ANALYSIS

Supervisors:

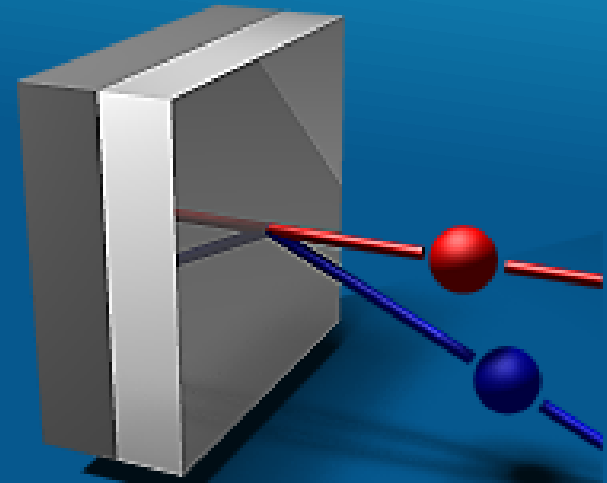
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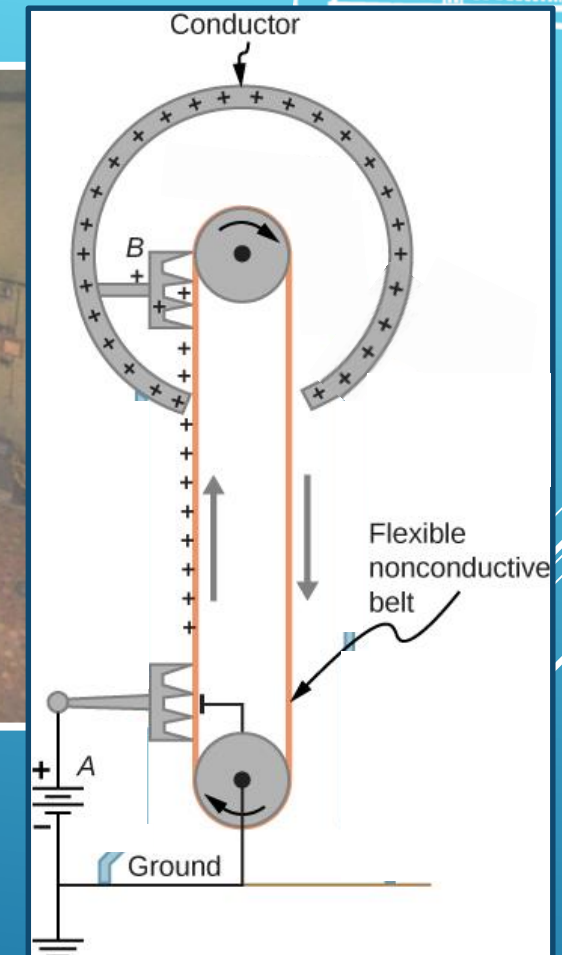
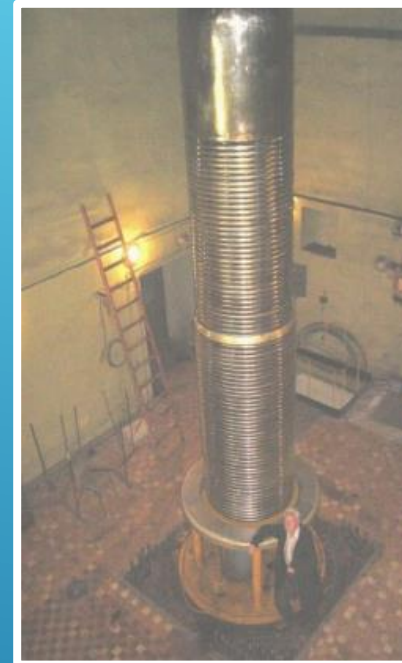


1. Van de Graaff accelerator
2. Rutherford backscattering spectrometry (RBS)
3. Experimental spectra of RBS and analysis
 - RBS sample – one layer systems
 - RBS samples - multilayer system
4. Nuclear reaction
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6. Conclusion analysis of ERD spectra

Characteristics of Van de Graaff accelerator (EG-5)



- This Generator was built in 1965.
- Ion source placed at the top part the accelerated tube
- Van de Graaff accelerator placed in a tank under pressure of 9 atmospheres of dry nitrogen.
- Energy : 0.9 – 3.5 MeV
- Beam intensity for H^+ : $30\mu A$
- Beam intensity for He^+ : $10\mu A$
- Energy spread : $< 500 eV$
- Energy precision: 2 keV
- Number of beam lines: 6



*A – electrical source
B – pointed conductor*

Scheme of Van de Graaff generator

Rutherford backscattering spectrometry (RBS)



- For near-surface layer analysis of solid
- Elemental composition without any standard
- Elemental depth profiles, dopants
- Analysing depth for He^+ ions is $2\ \mu\text{m}$ and for H^+ is $20\ \mu\text{m}$
- Sensitivity: for heavy elements – 0.01 at. %, and for light elements is less
- Typical depth resolution is 10-30 nm

Collision kinematics give information about the mass of the constituents.

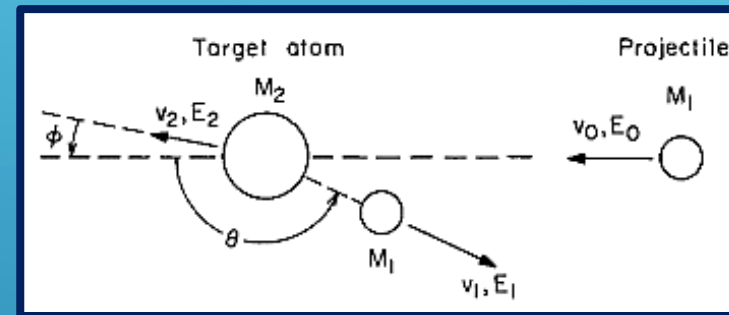


- Interaction between charged particle and atom is described by one elastic collision
- Was used laws of kinetic energy and momentum conservation

$$\frac{1}{2} M_1 v_0^2 = \frac{1}{2} M_1 v_1^2 + \frac{1}{2} M_2 v_2^2$$

$$M_1 v_0 = M_1 v_1 \cos \theta + M_2 v_2 \cos \phi$$

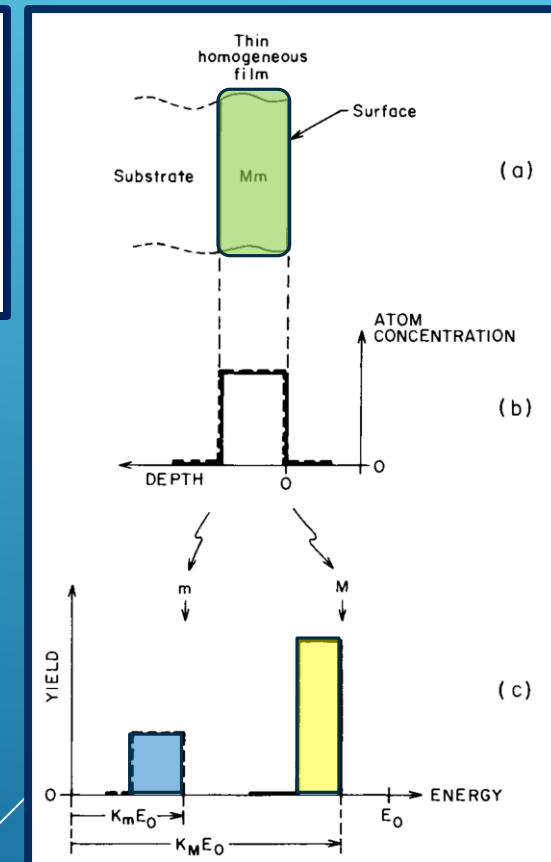
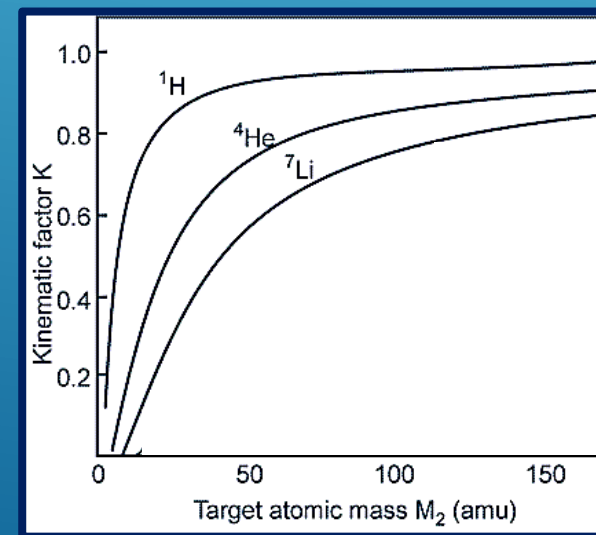
$$0 = M_1 v_1 \sin \theta - M_2 v_2 \sin \phi$$



$$\frac{v_1}{v_0} = \frac{[(M_2^2 - M_1^2 \sin^2 \theta)^{1/2} + M_1 \cos \theta]}{M_1 + M_2}$$

$$K = \frac{E_1}{E_0} = \left[\frac{(M_2^2 - M_1^2 \sin^2 \theta)^{1/2} + M_1 \cos \theta}{M_1 + M_2} \right]^2$$

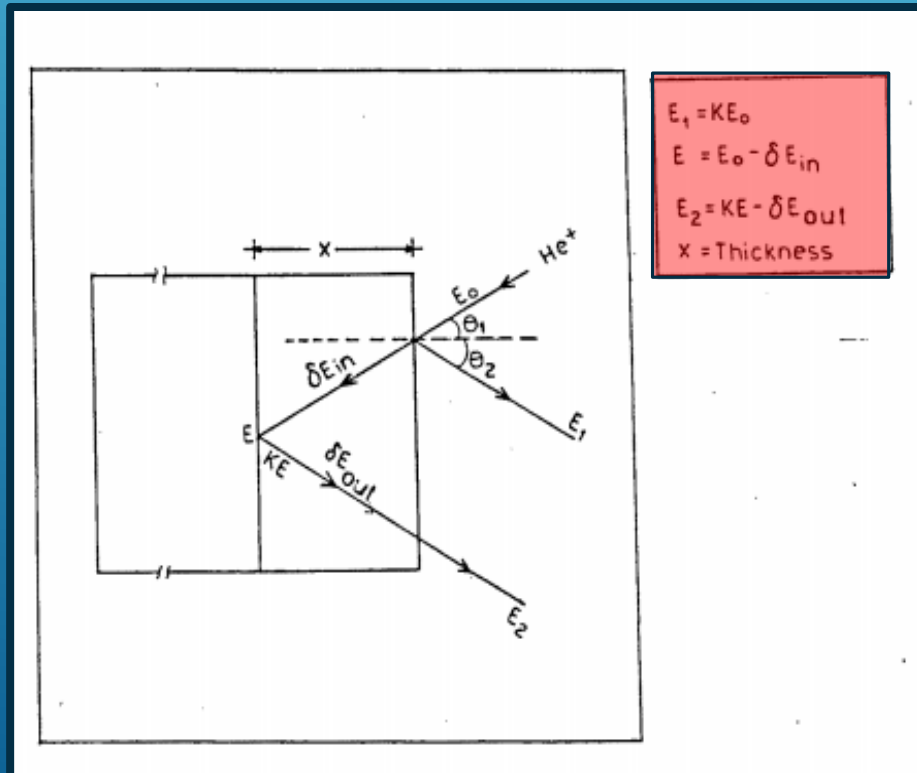
K – Kinematic factor



Rutherford cross section

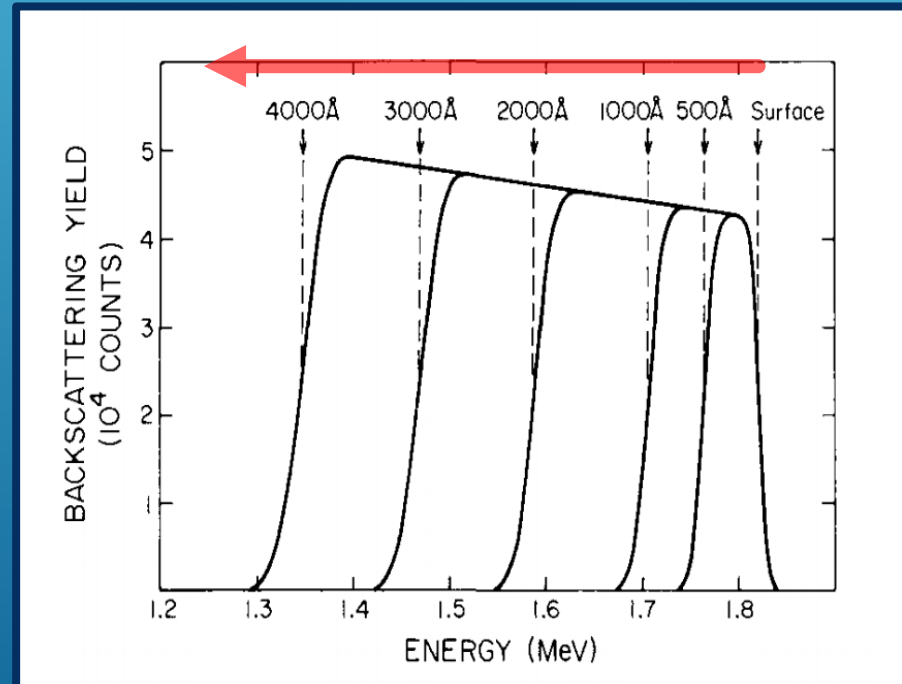


$$\frac{d\sigma}{d\Omega} = \left(\frac{Z_1 Z_2 e^2}{4E}\right)^2 \frac{4}{\sin^4 \theta} \frac{\left\{ \left[1 - \left(\frac{M_1}{M_2} \right) \sin^2 \theta \right]^{1/2} + \cos \theta \right\}^2}{\left[1 - \left(\frac{M_1}{M_2} \right) \sin^2 \theta \right]^{1/2}}$$

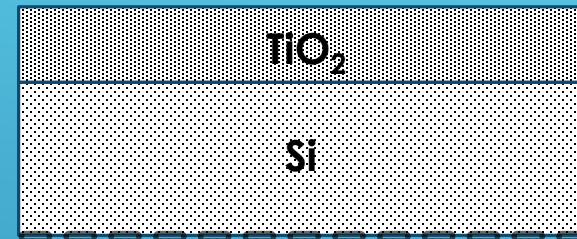
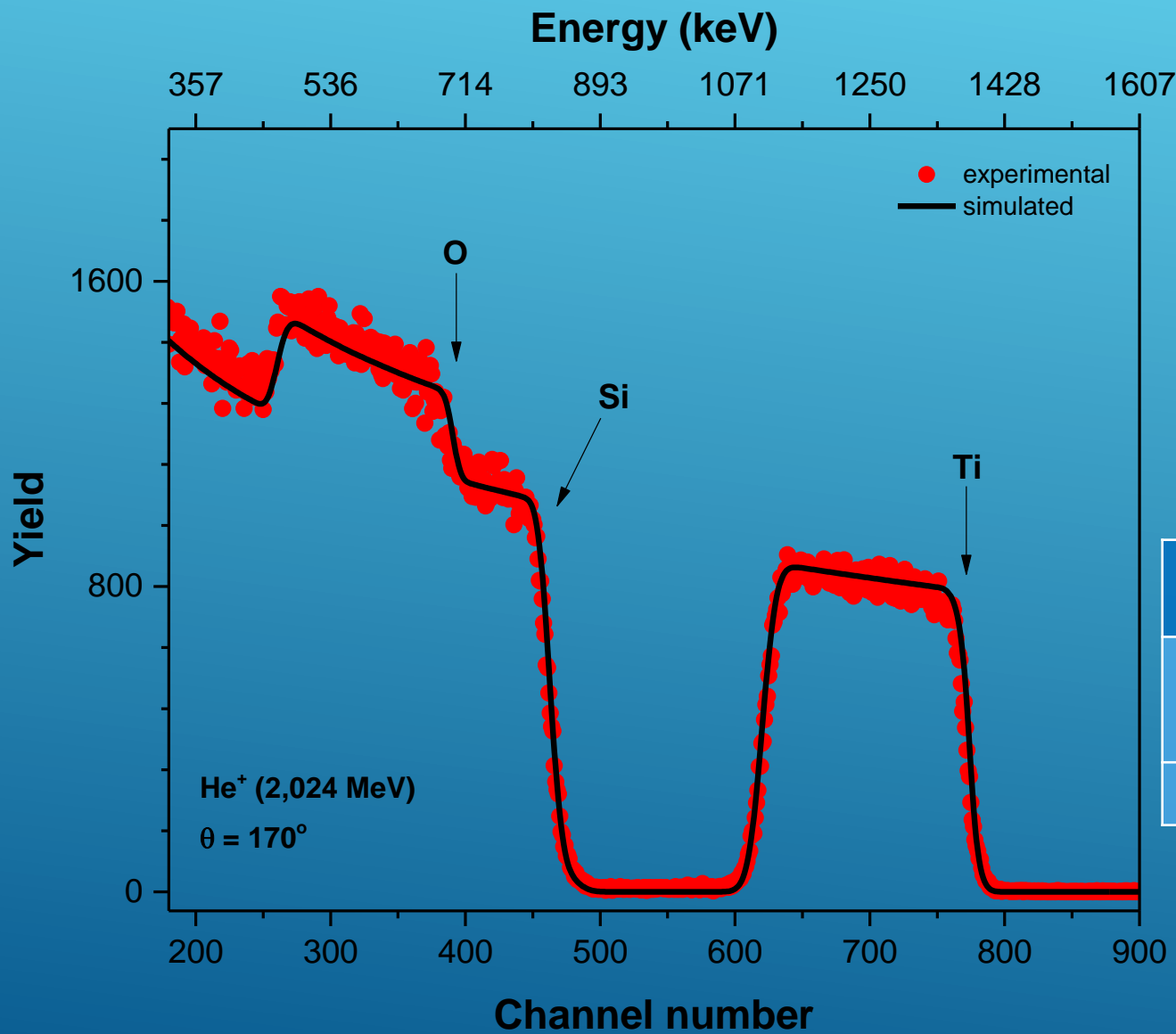


$$A = \sigma \Omega \cdot Q \cdot Nt.$$

(number of detected particles) = $\sigma \Omega \cdot$ (total number of incident particles) \cdot (number of target atoms per unit area).

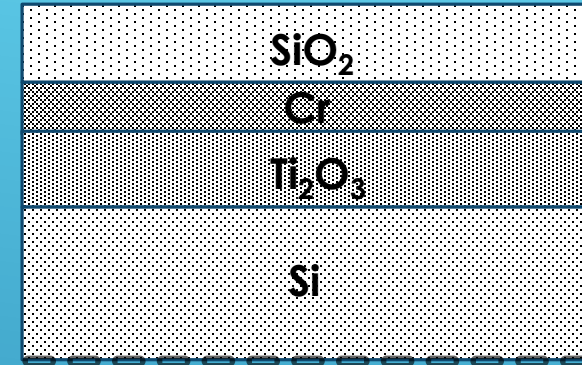
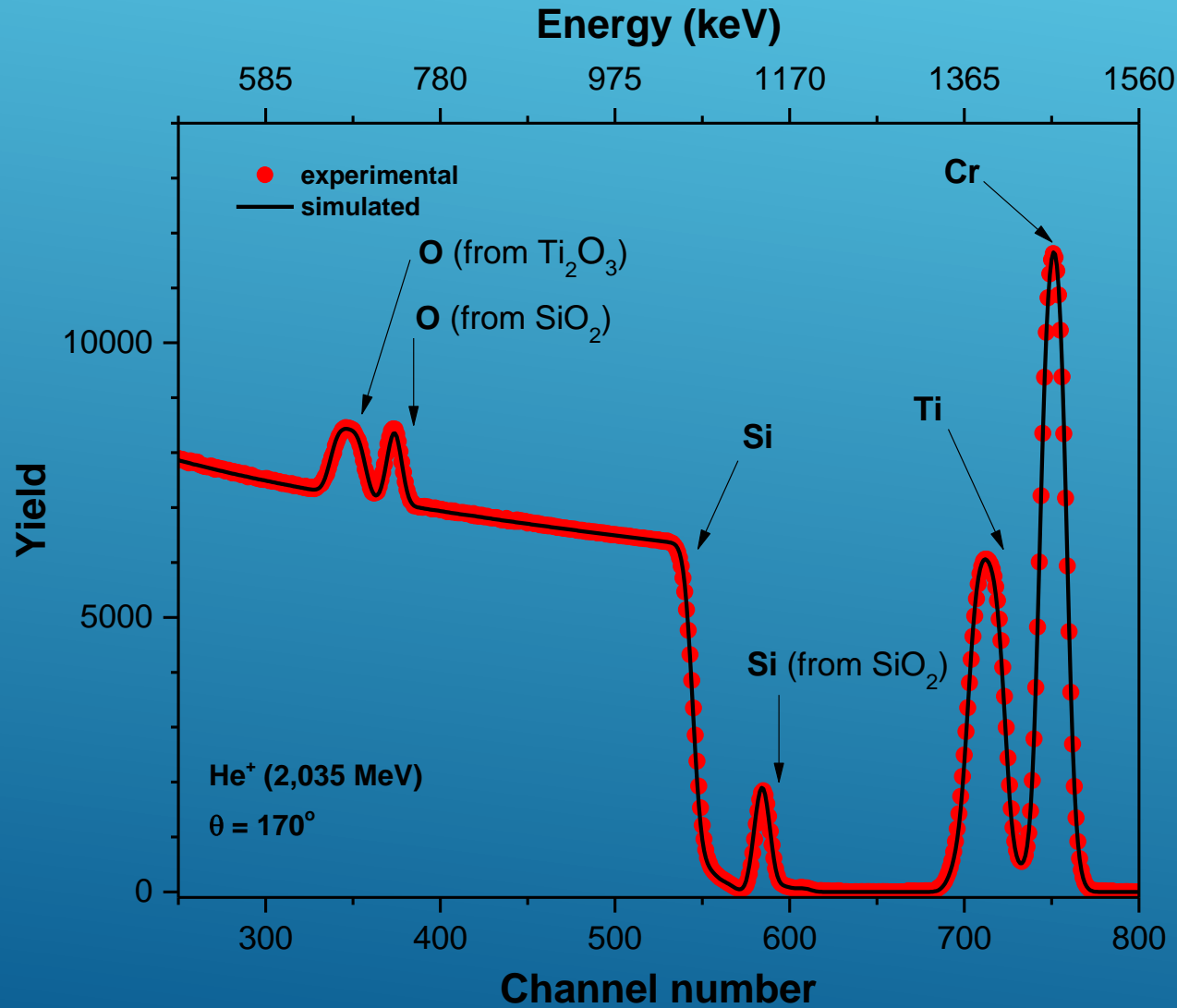


Example 1



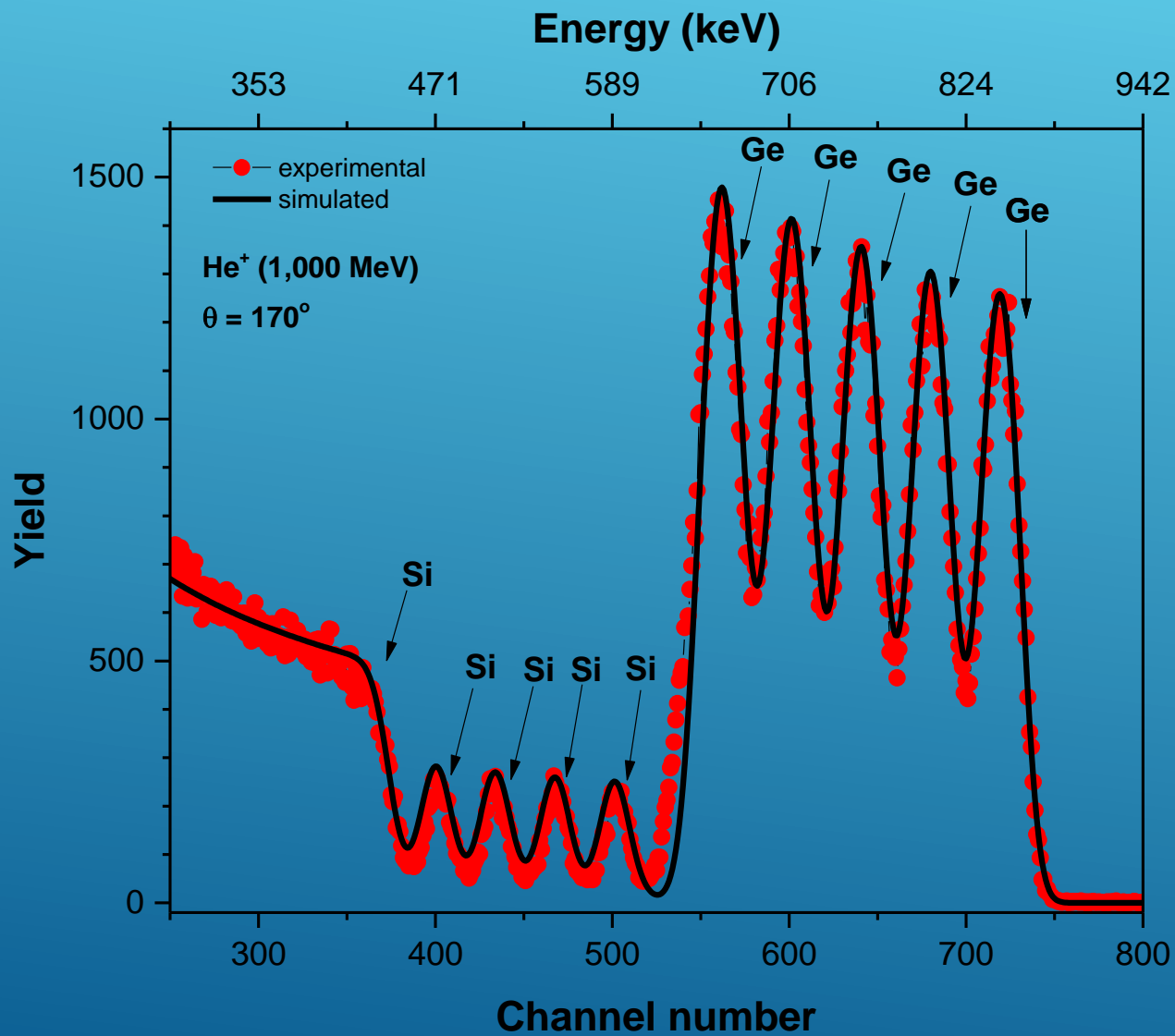
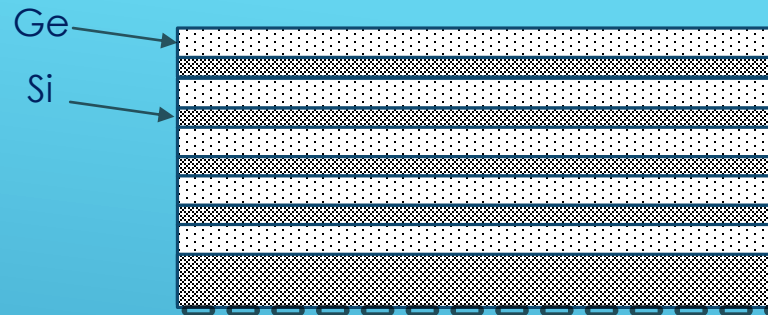
Number of layer	Element	Conc. (at. %)	Thickness (atom/ cm ²)*10 ¹⁵	Thickness (nm)
1	Ti	32	2980	316
	O	68		
2	Si	100	/	/

Example 2



Number of layer	Element	Conc. (at. %)	Thickness (atom/cm ²)*10 ¹⁵	Thickness (nm)
1	Si	33	180	23
	O	67		
2	Cr	100	200	24
3	Ti	41	400	42
	O	59		
4	Si	100	/	/

Example 3

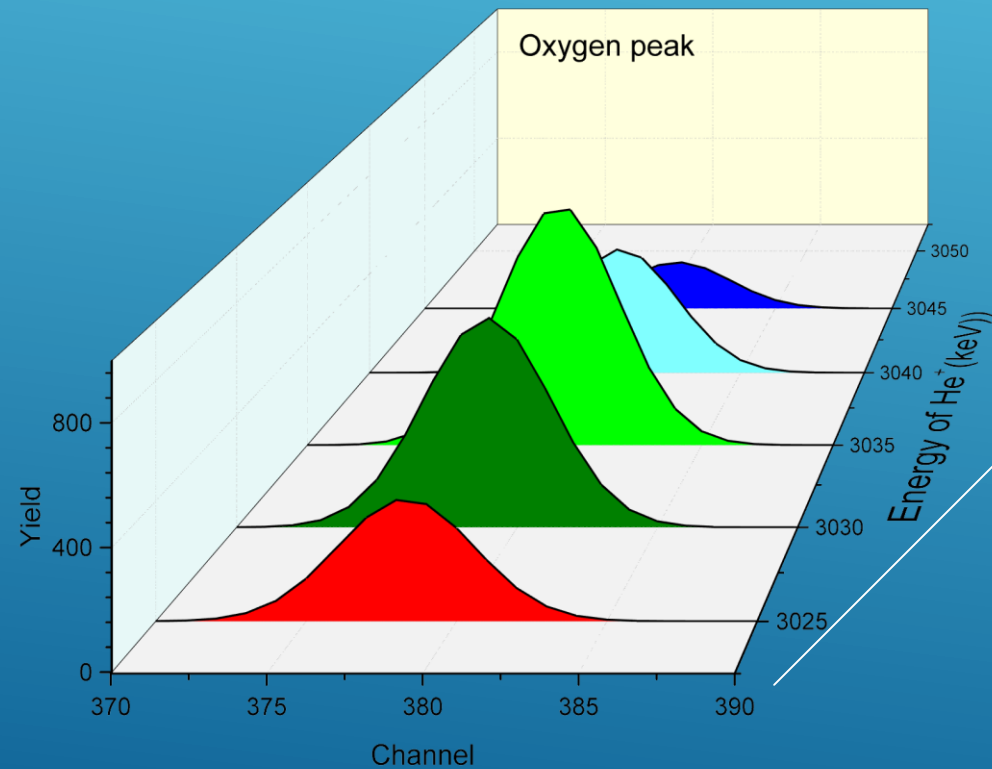
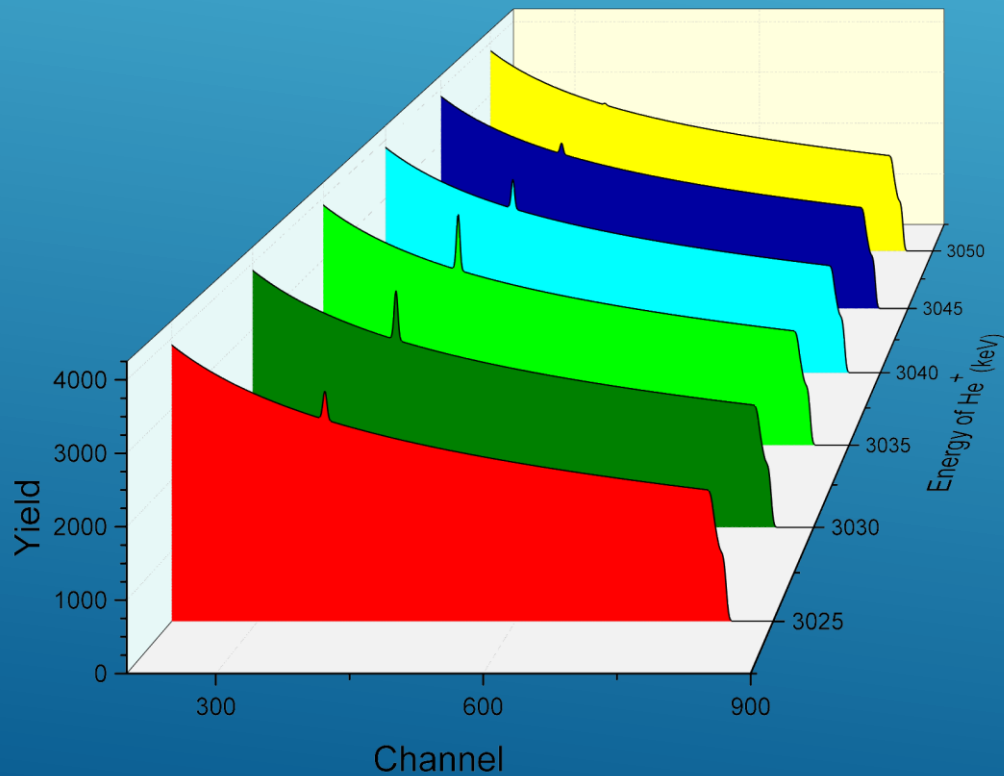


Number of layer	Element	Conc. (at. %)	Thickness (atom/ cm ²)*10 ¹⁵	Thickness (nm)
1	Ge	100	170	38
2	Si	100	140	28
3	Ge	100	170	38
4	Si	100	140	28
5	Ge	100	170	38
6	Si	100	140	28
7	Ge	100	170	38
8	Si	100	140	28
9	Ge	100	170	38
10	Si	100	/	/

Nuclear reaction method



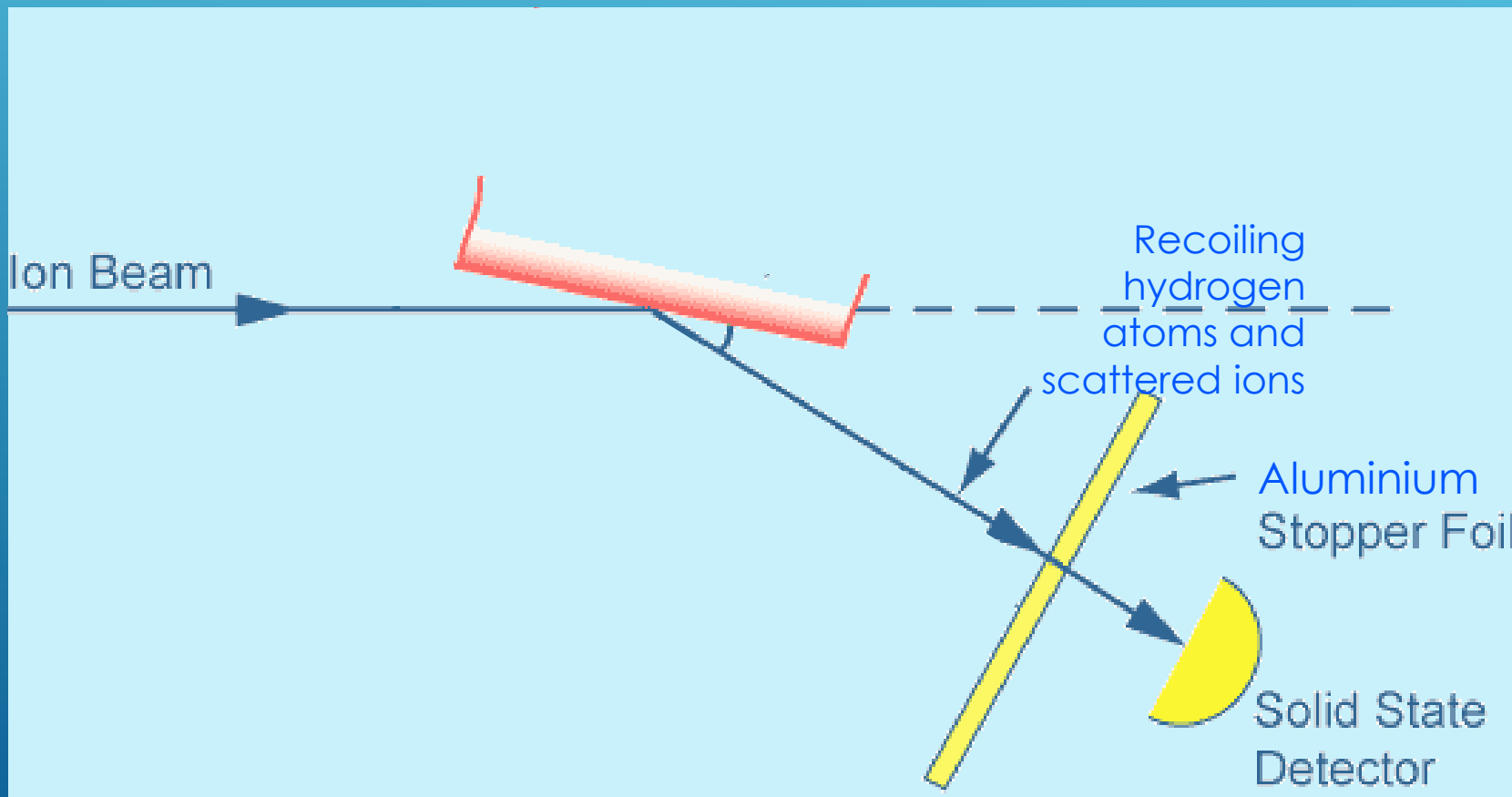
- Measurement of light element (oxygen) in thin layer on the surface GaAs will be improved using NR method



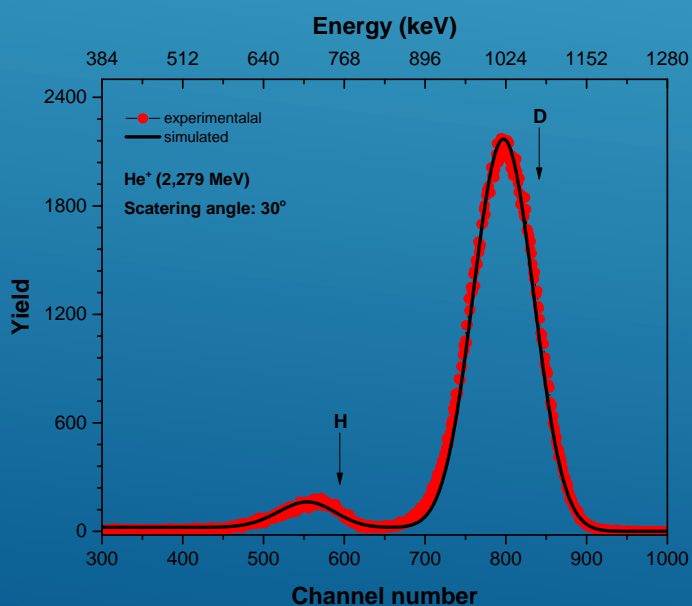
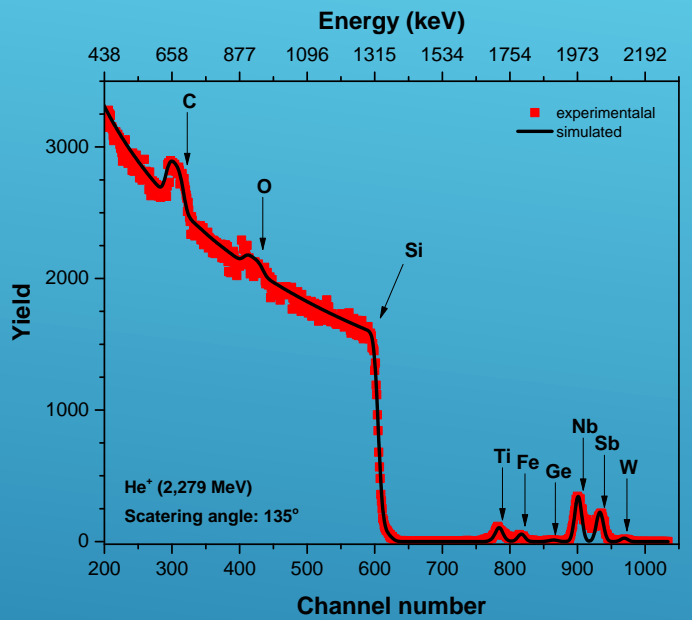
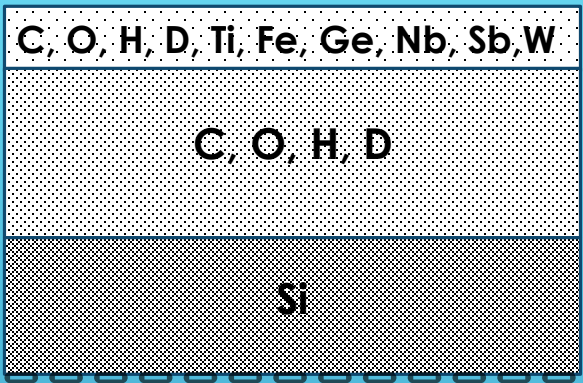
Elastic recoil detection (ERD)



- technique for depth profiling of light elements (isotopes of hydrogen) in multilayer systems



Example



Number of layer	Element	Conc. (at. %)	Thickness (atom/cm ²)*10 ¹⁵	Thickness (nm)
1	C	36.00	100	13
	O	5.26		
	Ti	5.30		
	Fe	1.80		
	Ge	0.30		
	Nb	4.20		
	Sb	1.80		
	W	0.10		
	H	10.00		
D	34.84			
2	C	34.00	1150	160
	O	5.50		
	H	20.00		
	D	40.50		
3	Si	100.00	/	/



Thank for your attention!

